


Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2380		SERIAL NO. Unknown 107655997	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Jon P. Daley			
				FILING DATE Filed Herewith 9/15/03		GROUP Unknown 2822	

U.S. PATENT DOCUMENTS							
Examiner's Initials	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
REP	AA	6,156,674	Li et al.				
REP	AB	6,281,100 B1	Ylin et al.				
REP	AC	6,291,363 B1	Yin et al.				
REP	AD	6,380,611 B1	Yin et al.				
REP	AE	6,383,723 B1	Iyer et al.				
REP	AF	10/177,056	Tran				06/21/2002
REP	AG	10/609,311	Yates				06/26/03
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
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*Examiner's Initials	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
PEP	AA	4,086,074	04/78	Minot et al.		
PEP	AB	4,622,735	11/86	Shibata		
PEP	AC	4,683,645	08/87	Naguib et al.		
PEP	AD	4,693,910	09/87	Nakajima et al.		
PEP	AE	4,766,090	08/88	Coquin et al.		
PEP	AF	5,099,304	03/92	Takemura et al.		
PEP	AG	5,236,865	08/93	Sandhu et al.		
PEP	AH	5,444,024	08/95	Anjum et al.		
PEP	AI	5,470,784	11/95	Anjum et al.		
FOREIGN PATENT DOCUMENTS						
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PEP	AM	ABSTRACT: Basceri et al., Atomic Layer Deposition for Nanoscale CU Metalization, 10 pages (pre-April 2004).				
PEP	AN	En et al., Plasma immersion ion implantation reactor design considerations for oxide charging, 85 SURFACE AND COATINGS TECHNOLOGY 64-69 (1966).				
PEP	AO	Ku et al., The Application of Ion Beam Mixing, Doped Silicide, and Rapid Thermal Processing of Self-Aligned Silicide Technology, 137 J. Electrochem. Soc. No. 2, pp. 728-740 (February 1990).				
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U.S. PATENT DOCUMENTS								
*Examiner's Initials	AA	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
REP	AA	5,670,298	09/97	Hur				
REP	AB	6,037,239	03/00	Jennings				
REP	AC	6,096,621	08/00	Jennings				
REP	AD	6,130,140	10/00	Gonzalez				
REP	AE	6,133,105	10/00	Chen et al.				
REP	AF	6,133,116	10/00	Kim et al.				
REP	AG	6,177,235 B1	01/01	Francou et al.				
REP	AH	6,277,709 B1	08/01	Wang et al.				
REP	AJ	6,277,728 B1	08/01	Ahn et al.				
FOREIGN PATENT DOCUMENTS								
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REP	AM		ABSTRACT: How to Eliminate Voiding in Porous-Low-k Dielectrics and The Mechanism of Void Formation; Lin et al.; 4 pages					
REP	AN		COB Stack DRAM Cell Technology beyond 100 nm Technology Node; Yongjik Park & Kinam Kim; pp. 349.1 - 349.3;					
REP	AO		Rubin et al., Shallow-Junction Diode Formation by implantation of Arsenic and Boron Through Titanium-Silicide Films and ..., 17 IEEE Transactions on Electron Devices, No. 1, pp. 183-190 (January 1990).					
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U.S. PATENT DOCUMENTS								
*Examiner's Initials	AA	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
PEP	AA	6,440,793 B1	08/02	Divakaruni et al.				
PEP	AB	6,465,325 B2	10/02	Ridley et al.				
PEP	AC	6,720,638 B2	04/04	Tran				
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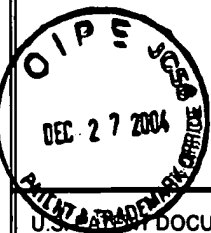

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PEP	AA	2001/0006759 A1	07/01	Shipley, Jr. et al.				
PEP	AB	2002/0076879 A1	06/02	Lee et al.				
PEP	AC	2002/0196651 A1	12/02	Weis				
PEP	AD	2003/0013272 A1	01/03	Hong et al.				
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REP	AA	10/689,958	Basceri			10/03	
REP	AB	10/690,029	Derderian et al.			10/03	
REP	AC	10/882,118	Sandhu et al.			04/04	
REP	AD	10/879,367	Blalock et al.			06/04	
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EXAMINER <i>P. J. [Signature]</i>			DATE CONSIDERED 2/16/05				
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U.S. PATENT DOCUMENTS								
*Examiner's Initials	AA	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
REP	AA	3,349,474	12/1963	D. H. Rauscher				
REP	AB	5,904,517	05/1999	Gardner et al.	438	197		
REP	AC	5,998,264	12/1999	Wu	438	260		
REP	AD	6,180,465 B1	01/2001	Gardner et al.	438	291		
REP	AE	6,207,485 B1	03/2001	Gardner et al.	438	216		
REP	AF	6,548,854 B1	04/2003	Kizilyalli et al.	257	310		
	AG							
REP	AH	2003/0045060 A1	03/2003	Ahn et al.	438	287		
REP	AI	2003/0045078 A1	03/2003	Ahn et al.	438	585		
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
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REP	AJ	EP 0 851 473 A2	01/1998	EPO			X	
	AK							
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
REP	AM	Chang et al., Silicon surface treatments in advanced MOS gate processing, Microelectronic Engineering, (2004), pages 130-135						
REP	AN	Lemberger et al., Electrical characterization and reliability aspects of zirconium silicate films obtained from novel MOCVD precursors, Microelectronic Engineering (2004), pages 315-320						
REP	AO	Lu et al., Effects of the TaN _x interface layer on doped tantalum oxide high- <i>k</i> films, VACUUM (2004), pages 1-9						
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[Signature]		4/16/05						
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							Yes	No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
RPD	AM		Robertson et al., Atomic structure, band offsets, growth and defects at high-K oxide:Si interfaces, Microelectronic Engineering (2004) pages 112-120					
RPD	AN		Singh et al., High and Low Dielectric Constant Materials, The Electrochemical Society <i>Interface</i> , Summer 1999, pages 26-30					
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U.S. PATENT DOCUMENTS							
*Examiner's Initials	AA	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
P&P		10/932,218		Basceri et al.	—		09/01/04
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PEP	AA	6,753,618	06/2004	Basceri et al.	257	915		
PEP	AB	5,470,794	11/1995	Anjum	437	200		
PEP	AC	2003/0219942 A1	11/2003	Choi et al.	438	253		
PEP	AD	2004/0245560 A1	12/2004	Pontoh et al.	257	309		
PEP	AE	2004/0245559 A1	12/2004	Pontoh et al.	257	306		
PEP	AF	2004/0046197 A1	03/2004	Basceri et al.	257	296		
PEP	AG	2004/0043228 A1	03/2004	Derderian et al.	428	446		
PEP	AH	2003/0213987 A1	11/2003	Basceri et al.	257	296		
PEP	AI	2003/0205729 A1	11/2003	Basceri et al.	257	200		
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